

Notice of References Cited

Application/Control No.

10/613,738

Applicant(s)/Patent Under
Reexamination
MCAULAY, ALASTAIR D.

Examiner

John Juba, Jr.

Art Unit

2872

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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